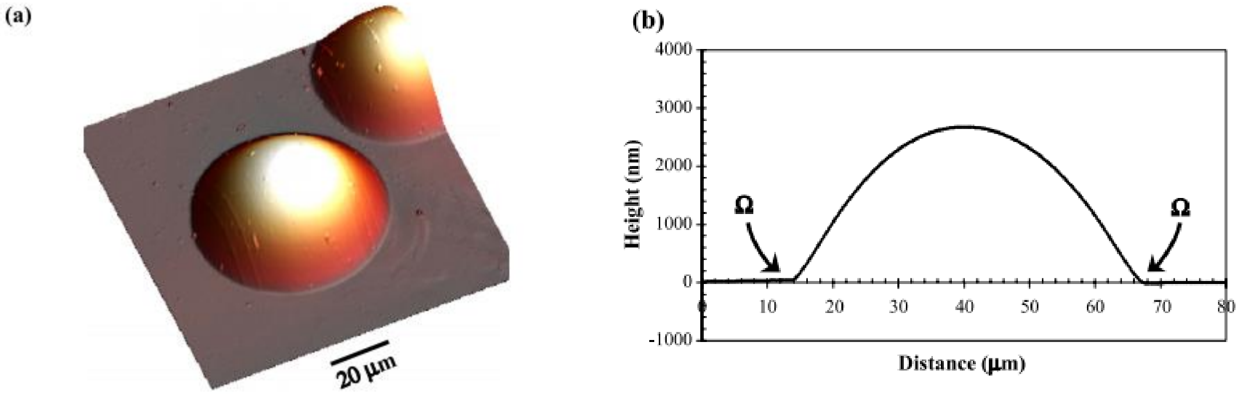

Figure 1: Figure 1: (a) 3D Atomic force microscopy micrograph of a circular buckle structure observed on a 600 nm thick gold film deposited on a silicon substrate (b) Cross section of the blister; A strong bending Ω on the edge of the buckling structure is observed (from Coupeau et al., 2004).

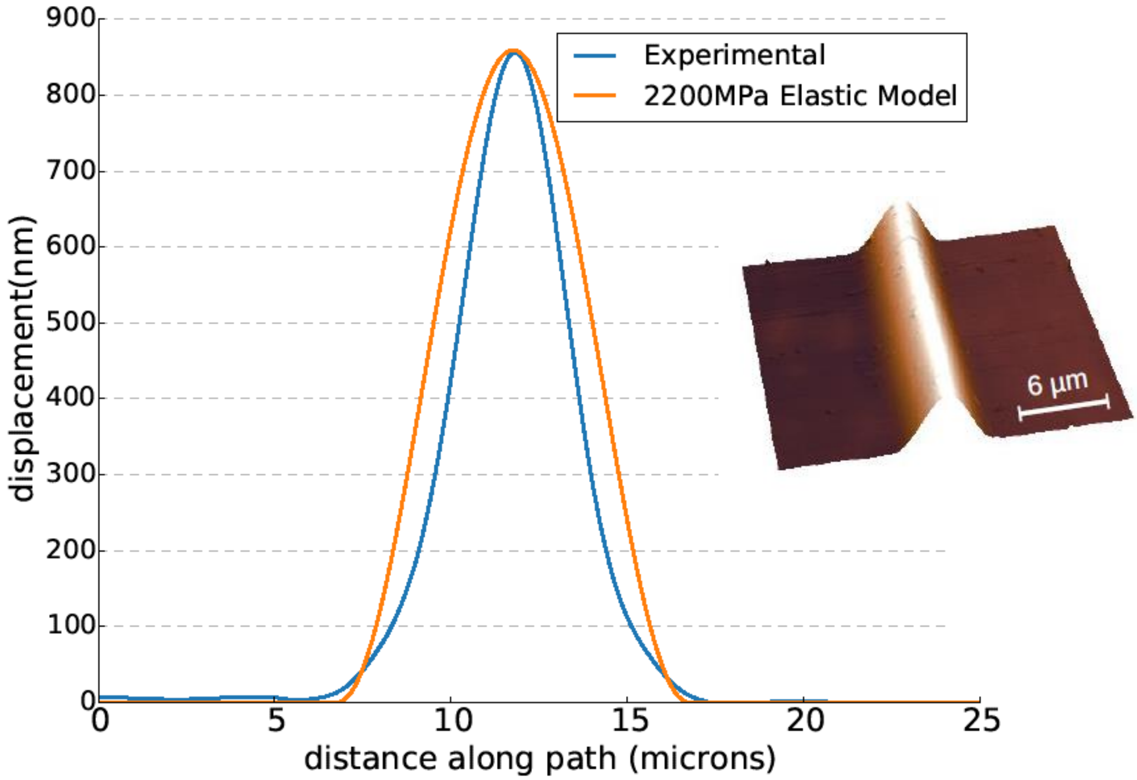

Figure 2: (right) 3D Atomic force microscopy micrograph of characteristic buckling structures observed on a 400 nm thick gold film deposited on a silicon substrate ; (left) Difference between the experimental profile and a numerical profile obtained with a pure elastic linear model.